




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/093,271	FUJII, TOSHIYA	
	Examiner	Art Unit	
	Son P. Huynh	2611	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
725		110		725	109	112	113	43	
INTERNATIONAL CLASSIFICATION				709	217	219			
H	0	4	N	7/173	345	715	723		
H	0	4	N	5/445	715	719	784	785	
G	0	6	F	15/16					
G	0	6	F	17/00					
G	0	9	G	5/00					

SON P. HUYNH 5/24/05 (Assistant Examiner) (Date)	 CHRIS GRANT PRIMARY EXAMINER (Primary Examiner)	Total Claims Allowed: 4
 (Legal Instruments Examiner) (Date)		O.G. Print Claim(s) 3

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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